## Applicant(s)/Patent Under Application/Control No. Reexamination 09/763,355 DE LANGE ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1725 Len Tran **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 422/145 02-1981 Daviduk et al. US-4,251,484 526/74 06-1995 Painter et al. В US-5,428,118 422/132 11-1993 Chinh et al. US-5,266,276 С US-D Ε US-US-F US-G US-Н 1 US-J US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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